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Interested committees:

Title: Draft BS EN IEC 60747-5-16 Semiconductor devices. Part 5-16: Optoelectronic devices - Light emitting diodes - Test method of the flat-band voltage based on the photocurrent spectroscopy.

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Introduction

This draft standard is based on national and international discussions. Your comments on this draft are invited and will assist in the preparation of the consequent standard.

For international standards, comments will be reviewed by the relevant UK national committee before sending the consensus UK vote and comments to the international committee, which will then decide appropriate action. If the international standard is approved, it is usual for the text to be published as a British Standard.

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Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx
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1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex (e.g. 3.1)	Paragraph/Figure/ Table/Note	Type of comment	Commend (justification for change) by the MB	Proposed change by the MB	Secretariat observations on each comment submitted
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	



47E/772/CD

COMMITTEE DRAFT (CD)

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2022-02-18

SUPERSEDES DOCUMENTS:

47E/743A/NP, 47E/759/RVN

IEC SC 47E : DISCRETE SEMICONDUCTOR DEVICES	
SECRETARIAT: Korea, Republic of	SECRETARY: Mr Hojun Ryu
OF INTEREST TO THE FOLLOWING COMMITTEES:	PROPOSED HORIZONTAL STANDARD: ☐ Other TC/SCs are requested to indicate their interest, if any, in this CD to the secretary.
FUNCTIONS CONCERNED: ☐ EMC ☐ ENVIRONMENT ☐ QUALITY ASSURANCE ☐ SAFETY	

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Recipients of this document are invited to submit, with their comments, notification of any relevant patent rights of which they are aware and to provide supporting documentation.

TITLE:

Semiconductor devices - Part 5-16: Optoelectronic devices - Light emitting diodes - Test method of the flat-band voltage based on the photocurrent spectroscopy

NOTE FROM TC/SC OFFICERS:

This CD was prepared based on the result of discussions at the SC 47E / WG 9 meeting held online on October 6, 2021.

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES –

**Part 5-16: Optoelectronic devices – Light emitting diodes –
Test method of the flat-band voltage based on
the photocurrent spectroscopy**

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IEC 60747-5-16 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices. It is an International Standard.

The text of this International Standard is based on the following documents:

Draft	Report on voting
47E/XX/FDIS	47E/XX/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

91 A list of all parts in the IEC 60747 series, published under the general title *Semiconductor devices*,
92 can be found on the IEC website.

93 The committee has decided that the contents of this document will remain unchanged until the stability
94 date indicated on the IEC website under webstore.iec.ch in the data related to the specific document.
95 At this date, the document will be

- 96 • reconfirmed,
97 • withdrawn,
98 • replaced by a revised edition, or
99 • amended.

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